# 74ALVC164245

# 16-bit dual supply translating transceiver; 3-state

Rev. 8 — 15 March 2012

**Product data sheet** 

### 1. General description

The 74ALVC164245 is a high-performance, low-power, low-voltage, Si-gate CMOS device, superior to most advanced CMOS compatible TTL families.

The 74ALVC164245 is a 16-bit (dual octal) dual supply translating transceiver featuring non-inverting 3-state bus compatible outputs in both send and receive directions. It is designed to interface between a 3 V and 5 V bus in a mixed 3 V and 5 V supply environment.

This device can be used as two 8-bit transceivers or one 16-bit transceiver.

The direction control inputs (1DIR and 2DIR) determine the direction of the data flow. nDIR (active HIGH) enables data from nAn ports to nBn ports. nDIR (active LOW) enables data from nBn ports to nAn ports. The output enable inputs (1 $\overline{OE}$  and 2 $\overline{OE}$ ), when HIGH, disable both nAn and nBn ports by placing them in a high-impedance OFF-state. Pins nAn, n $\overline{OE}$  and nDIR are referenced to  $V_{CC(A)}$  and pins nBn are referenced to  $V_{CC(B)}$ .

In suspend mode, when one of the supply voltages is zero, there will be no current flow from the non-zero supply towards the zero supply. The nAn-outputs must be set 3-state and the voltage on the A-bus must be smaller than  $V_{diode}$  (typical 0.7 V).  $V_{CC(B)} \ge V_{CC(A)}$  (except in suspend mode).

### 2. Features and benefits

- 5 V tolerant inputs/outputs for interfacing with 5 V logic
- Wide supply voltage range:
  - ◆ 3 V port (V<sub>CC(A)</sub>): 1.5 V to 3.6 V
  - ◆ 5 V port (V<sub>CC(B)</sub>): 1.5 V to 5.5 V
- CMOS low power consumption
- Direct interface with TTL levels
- Control inputs voltage range from 2.7 V to 5.5 V
- Inputs accept voltages up to 5.5 V
- High-impedance outputs when V<sub>CC(A)</sub> or V<sub>CC(B)</sub> = 0 V
- Complies with JEDEC standard JESD8-B/JESD36
- ESD protection:
  - HBM JESD22-A114F exceeds 2000 V
  - ♦ MM JESD22-A115-A exceeds 200 V
- Specified from -40 °C to +85 °C and -40 °C to +125 °C

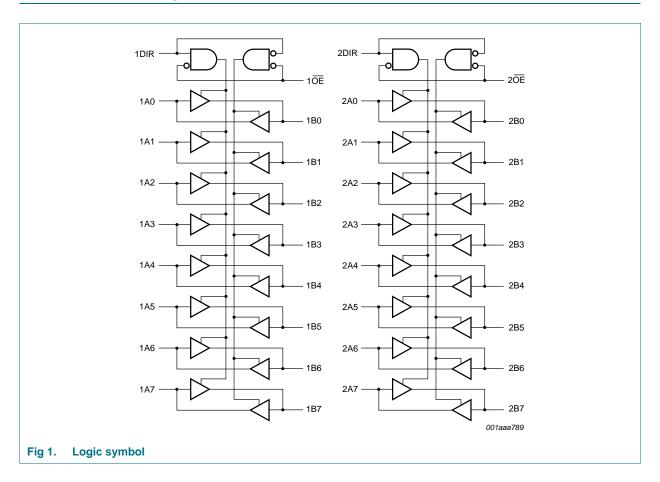


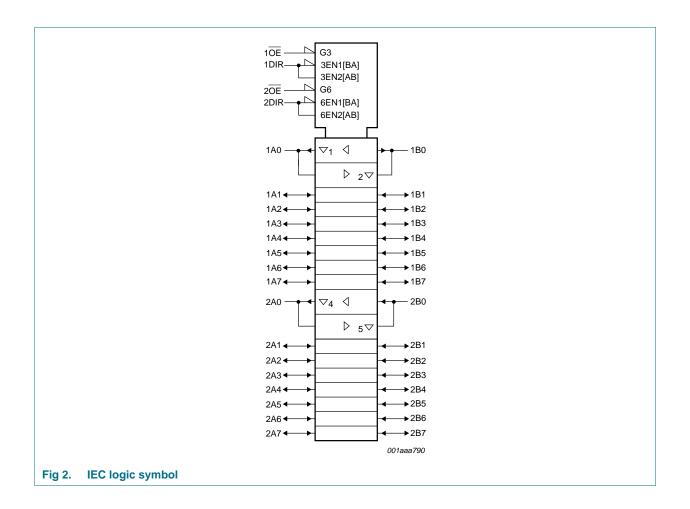
# 3. Ordering information

Table 1. Ordering information

Type number	Temperature	Package	Package						
	range	Name	Description	Version					
74ALVC164245DL	-40 °C to +125 °C	SSOP48	plastic shrink small outline package; 48 leads; body width 7.5 mm	SOT370-1					
74ALVC164245DGG	–40 °C to +125 °C	TSSOP48	plastic thin shrink small outline package; 48 leads; body width 6.1 mm	SOT362-1					
74ALVC164245BX	–40 °C to +125 °C	HXQFN60	plastic compatible thermal enhanced extremely thin quad flat package; no leads; 60 terminals; body $4\times6\times0.5$ mm	SOT1134-2					

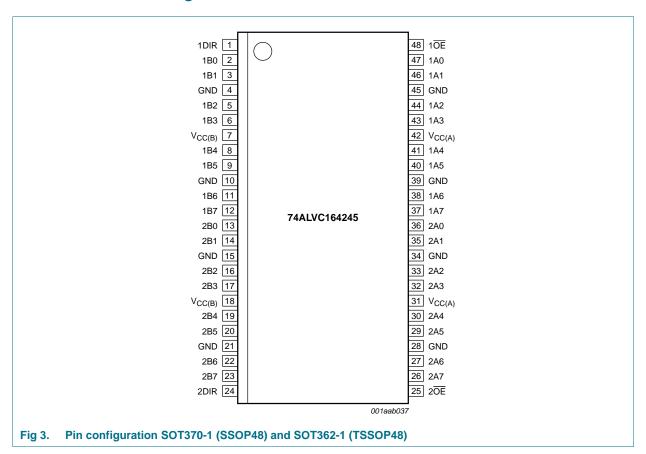
# 4. Functional diagram





# 5. Pinning information

### 5.1 Pinning



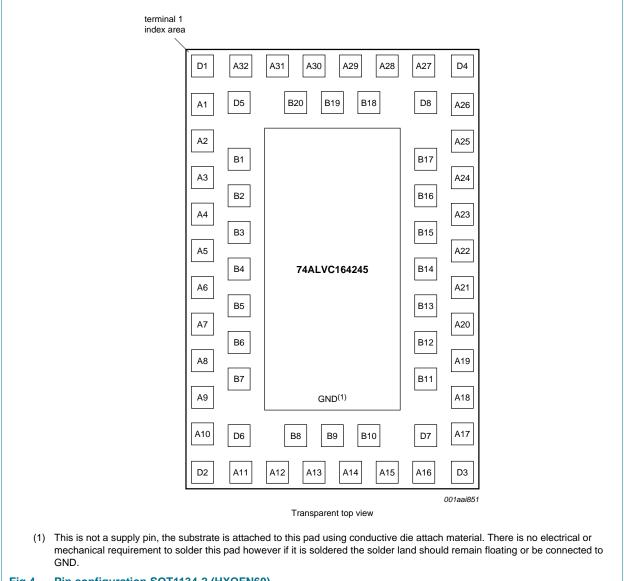


Fig 4. Pin configuration SOT1134-2 (HXQFN60)

### 5.2 Pin description

Table 2. Pin description

Symbol	Pin		Description	
	SOT370-1 and SOT362-1	SOT1134-2		
1DIR, 2DIR	1, 24	A30, A13	direction control input	
1B0 to 1B7	2, 3, 5, 6, 8, 9, 11, 12	B20, A31, D5, D1, A2, B2, B3, A5	data input/output	
2B0 to 2B7	13, 14, 16, 17, 19, 20, 22, 23	A6, B5, B6, A9, D2, D6, A12, B8	data input/output	
GND	4, 10, 15, 21, 28, 34, 39, 45	A32, A3, A8, A11, A16, A19, A24, A27	ground (0 V)	
$V_{CC(B)}$	7, 18	A1, A10,	supply voltage B (5 V bus)	
10E, 20E	48, 25	A29, A14	output enable input (active LOW)	
1A0 to 1A7	47, 46, 44, 43, 41, 40, 38, 37	B18, A28, D8, D4, A25, B16, B15, A22	data input/output	
2A0 to 2A7	36, 35, 33, 32, 30, 29, 27, 26	A21, B13, B12, A18, D3, D7, A15, B10	data input/output	
$V_{CC(A)}$	31, 42	A17, A26	supply voltage A (3 V bus)	
n.c.	-	A4, A7, A20, A23, B1, B4, B7, B9, B11, B14, B17, B19	not connected	

# 6. Functional description

Table 3. Function table[1]

Inputs		Outputs			
nOE	nDIR	nAn	nBn		
L	L	nAn = nBn	inputs		
L	Н	inputs	nBn = nAn		
Н	X	Z	Z		

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V). See [1].

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC(B)}$	supply voltage B	$V_{CC(B)} \ge V_{CC(A)}$	-0.5	+6.0	V
$V_{CC(A)}$	supply voltage A	$V_{CC(B)} \ge V_{CC(A)}$	-0.5	+4.6	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-50	-	mA
$V_{I}$	input voltage		<u>[2]</u> –0.5	+6.0	V
V <sub>I/O</sub>	input/output voltage		-0.5	$V_{CC} + 0.5$	V
I <sub>OK</sub>	output clamping current	$V_O > V_{CC}$ or $V_O < 0 V$	-	±50	mA
$V_{O}$	output voltage	output HIGH or LOW	<u>[2]</u> –0.5	$V_{CC} + 0.5$	V
		output 3-state	<u>[2]</u> –0.5	+6.0	V
I <sub>O(sink/source)</sub>	output sink or source current	$V_O = 0 V \text{ to } V_{CC}$	-	±50	mA
I <sub>CC</sub>	supply current		-	100	mA

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Table 4. Limiting values ...continued

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V). See [1].

Symbol	Parameter	Conditions	Min	Max	Unit
$I_{GND}$	ground current		-100	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation $T_{amb} = -40 \text{ °C to } +125 \text{ °C}$				
		(T)SSOP48 package	<u>[3]</u> _	500	mW
		HXQFN60 package	<u>[4]</u> _	1000	mW

<sup>[1]</sup> The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

# 8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{CC(B)}$	supply voltage B	$V_{CC(B)} \ge V_{CC(A)}$				
		maximum speed performance	2.7	-	5.5	V
		low-voltage applications	1.5	-	5.5	V
V <sub>CC(A)</sub>	supply voltage A	$V_{CC(B)} \ge V_{CC(A)}$				
		maximum speed performance	2.7	-	3.6	V
		low-voltage applications	1.5	-	3.6	V
VI	input voltage	control inputs: nOE and nDIR	0	-	5.5	V
V <sub>I/O</sub>	input/output voltage	nAn port	0	-	$V_{CC(A)}$	V
		nBn port	0	-	$V_{CC(B)}$	V
Vo	output voltage	nAn port	0	-	$V_{CC(A)}$	V
		nBn port	0	-	$V_{CC(B)}$	V
T <sub>amb</sub>	ambient temperature		-40	-	+125	°C
$\Delta t/\Delta V$	input transition rise	$V_{CC(A)} = 2.7 \text{ V to } 3.0 \text{ V}$	0	-	20	ns/V
	and fall rate	$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V}$	0	-	10	ns/V
		$V_{CC(B)} = 3.0 \text{ V to } 4.5 \text{ V}$	0	-	20	ns/V
		$V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$	0	-	10	ns/V

<sup>[2]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>[3]</sup> Above 60 °C the value of  $P_{tot}$  derates linearly with 5.5 mW/K.

<sup>[4]</sup> Above 70 °C the value of  $P_{tot}$  derates linearly with 1.8 mW/K.

# 9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		$T_{amb} = -40$	°C to +8	35 °C	$T_{amb} = -40$ °C to +125 °C			Unit
				Min	Typ[1]	Max	Min	Typ[1]	Max	
V <sub>IH</sub>	HIGH-level	nBn port					1	1		
	input voltage	$V_{CC(B)} = 3.0 \text{ V to } 5.5 \text{ V}$	[2]	2.0	-	-	2.0	-	-	V
		nAn port, nOE and nDIR								
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V}$		2.0	-	-	2.0	-	-	V
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V}$	[2]	1.7	-	-	1.7	-	-	٧
V <sub>IL</sub>	LOW-level	nBn port								
	input voltage	$V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$	[2]	-	-	0.8	-	-	0.8	V
		$V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$	[2]	-	-	0.7	-	-	0.7	V
		nAn port, nOE and nDIR								
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V}$		-	-	0.8	-	-	0.8	٧
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V}$	[2]	-	-	0.7	-	-	0.7	V
V <sub>OH</sub>	HIGH-level	nBn port; $V_I = V_{IH}$ or $V_{IL}$								
	output voltage	$I_{O} = -24 \text{ mA}; V_{CC(B)} = 4.5 \text{ V}$		V <sub>CC(B)</sub> - 0.8	-	-	V <sub>CC(B)</sub> - 1.2	-	-	V
		$I_O = -12 \text{ mA}; V_{CC(B)} = 4.5 \text{ V}$		V <sub>CC(B)</sub> - 0.5	-	-	V <sub>CC(B)</sub> - 0.8	-	-	V
		$I_O = -18 \text{ mA}; V_{CC(B)} = 3.0 \text{ V}$		V <sub>CC(B)</sub> - 0.8	-	-	V <sub>CC(B)</sub> - 1.0	-	-	V
		$I_O = -100 \mu A; V_{CC(B)} = 3.0 \text{ V}$		V <sub>CC(B)</sub> - 0.2	V <sub>CC(B)</sub>	-	V <sub>CC(B)</sub> - 0.3	V <sub>CC(B)</sub>	-	V
		nAn port; $V_I = V_{IH}$ or $V_{IL}$								
		$I_{O} = -24 \text{ mA}; V_{CC(A)} = 3.0 \text{ V}$		V <sub>CC(A)</sub> - 0.7	-	-	V <sub>CC(A)</sub> - 1.0	-	-	V
		$I_O = -100 \mu A; V_{CC(A)} = 3.0 \text{ V}$		V <sub>CC(A)</sub> - 0.2	-	-	V <sub>CC(A)</sub> - 0.3	-	-	V
		$I_{O} = -12 \text{ mA}; V_{CC(A)} = 2.7 \text{ V}$		V <sub>CC(A)</sub> - 0.5	-	-	V <sub>CC(A)</sub> - 0.8	-	-	V
		$I_O = -8 \text{ mA}; V_{CC(A)} = 2.3 \text{ V}$		V <sub>CC(A)</sub> - 0.6	-	-	V <sub>CC(A)</sub> - 0.6	-	-	V
		$I_O = -100 \mu A; V_{CC(A)} = 2.3 \text{ V}$		V <sub>CC(A)</sub> - 0.2	$V_{CC(A)}$	-	V <sub>CC(A)</sub> - 0.3	$V_{CC(A)}$	-	V
V <sub>OL</sub>	LOW-level	nBn port; $V_I = V_{IH}$ or $V_{IL}$								
	output voltage	$I_O = 24 \text{ mA}; V_{CC(B)} = 4.5 \text{ V}$		-	-	0.55	-	-	0.60	V
		$I_O = 12 \text{ mA}; V_{CC(B)} = 4.5 \text{ V}$		-	-	0.40	-	-	0.80	V
		$I_O = 100 \mu A; V_{CC(B)} = 4.5 \text{ V}$		-	-	0.20	-	-	0.30	V
		$I_O = 18 \text{ mA}; V_{CC(B)} = 3.0 \text{ V}$		-	-	0.55	-	-	0.80	V
		$I_O = 100 \mu A; V_{CC(B)} = 3.0 \text{ V}$		-	-	0.20	-	-	0.30	٧
		nAn port; $V_I = V_{IH}$ or $V_{IL}$								
		$I_O = 24 \text{ mA}; V_{CC(A)} = 3.0 \text{ V}$		-	-	0.55	-	-	0.80	V
		$I_O = 100 \mu A; V_{CC(A)} = 3.0 \text{ V}$		-	-	0.20	-	-	0.30	V
		$I_O = 12 \text{ mA}; V_{CC(A)} = 2.7 \text{ V}$		-	-	0.40	-	-	0.60	V
		$I_O = 12 \text{ mA}; V_{CC(A)} = 2.3 \text{ V}$		-	-	0.60	-	-	0.60	V
		$I_O = 100 \mu A; V_{CC(A)} = 2.3 \text{ V}$		-	-	0.20	-	-	0.20	V
I	input leakage current	V <sub>I</sub> = 5.5 V or GND		-	±0.1	±5	-	±0.1	±10	μΑ
l <sub>oz</sub>	OFF-state output current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	[3]	-	±0.1	±10	-	±0.1	±20	μΑ
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Table 6. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +85  ^{\circ}\text{C}$			$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C}$		
			Min	Typ[1]	Max	Min	Typ[1]	Max	
$I_{CC}$	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A	-	0.1	40	-	0.1	80	μΑ
$\Delta I_{CC}$	additional supply current	per control pin; $V_I = V_{CC} - 0.6 \text{ V}; I_O = 0 \text{ A}$	-	5	500	-	5	5000	μΑ
Cı	input capacitance		-	4.0	-	-	-	-	pF
C <sub>I/O</sub>	input/output capacitance	nAn and nBn port	-	5.0	-	-	-	-	pF

<sup>[1]</sup> All typical values are measured at  $V_{CC(B)} = 5.0 \text{ V}$ ,  $V_{CC(A)} = 3.3 \text{ V}$  and  $T_{amb} = 25 \,^{\circ}\text{C}$ .

# 10. Dynamic characteristics

Table 7. Dynamic characteristics

GND = 0 V;  $t_r = t_f \le 2.5$  ns;  $C_L = 50$  pF; for test circuit see <u>Figure 7</u>.

Symbol	Parameter	Conditions	Conditions	T <sub>amb</sub> = -	-40 °C to	+85 °C	T <sub>amb</sub> = -40 °	C to +125 °C	Unit
				Min	Typ[1]	Max	Min	Max	
$t_{pd}$	propagation	nAn to nBn; see Figure 5	[2]						
	delay	$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		1.5	3.3	7.6	1.5	9.5	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.0	3.0	5.9	1.0	7.5	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.0	2.9	5.8	1.0	7.5	ns
		nBn to nAn; see Figure 5	[2]						
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		1.0	3.0	7.6	1.0	9.5	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.0	4.3	6.7	1.0	8.5	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.2	2.5	5.8	1.2	7.5	ns

<sup>[2]</sup> If  $V_{CC(A)}$  < 2.7 V, the switching levels at all inputs are not TTL compatible.

<sup>[3]</sup> For transceivers, the parameter I<sub>OZ</sub> includes the input leakage current.

<sup>[4]</sup>  $V_{CC(A)} = 2.7 \text{ V}$  to 3.6 V: other inputs at  $V_{CC(A)}$  or GND;  $V_{CC(B)} = 4.5 \text{ V}$  to 5.5 V: other inputs at  $V_{CC(B)}$  or GND.

**Table 7. Dynamic characteristics** ...continued  $GND = 0 \ V; \ t_r = t_f \le 2.5 \ ns; \ C_L = 50 \ pF; \ for test circuit see <u>Figure 7</u>.$ 

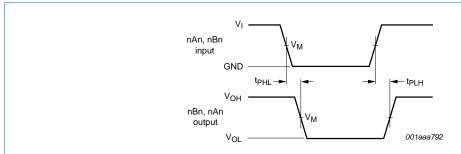
Symbol	Parameter	Conditions		T <sub>amb</sub> = -	-40 °C to	+85 °C	T <sub>amb</sub> = -40 °C	C to +125 °C	Unit
				Min	Typ[1]	Max	Min	Max	
t <sub>en</sub>	enable time	nOE to nBn; see Figure 6	[2]				'		
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		1.5	4.1	11.5	1.5	14.5	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.5	3.6	9.2	1.5	11.5	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.0	3.2	8.9	1.0	12.0	ns
		nOE to nAn; see Figure 6	[2]						
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		1.5	4.6	12.3	1.5	15.5	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.5	4.3	9.3	1.5	12.0	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.0	3.2	8.9	1.0	11.5	ns
t <sub>dis</sub>	disable time	nOE to nBn; see Figure 6	[2]						
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		2.0	2.7	10.5	2.0	13.5	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		2.5	4.6	9.0	2.5	11.5	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		2.1	4.9	8.6	2.1	11.0	ns
		nOE to nAn; see Figure 6	[2]						
		$V_{CC(A)} = 2.3 \text{ V to } 2.7 \text{ V};$ $V_{CC(B)} = 3.0 \text{ V to } 3.6 \text{ V}$		1.0	2.7	9.3	1.0	12.0	ns
		$V_{CC(A)} = 2.7 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		1.5	3.5	9.0	1.5	11.5	ns
		$V_{CC(A)} = 3.0 \text{ V to } 3.6 \text{ V};$ $V_{CC(B)} = 4.5 \text{ V to } 5.5 \text{ V}$		2.0	3.2	8.6	2.0	11.0	ns

**Table 7. Dynamic characteristics** ...continued  $GND = 0 \ V; \ t_r = t_f \le 2.5 \ ns; \ C_L = 50 \ pF; for test circuit see <u>Figure 7</u>.$ 

Symbol	Parameter	Conditions	Conditions		-40 °C to	+85 °C	T <sub>amb</sub> = -40 °	C to +125 °C	Unit
				Min	Typ[1]	Max	Min	Max	
dis	power dissipation	5 V port: nAn to nBn; $V_{CC(B)} = 5 \text{ V}; V_{CC(A)} = 3.3 \text{ V}$	[3][4]						
	capacitance	outputs enabled		-	30	-	-	-	pF
		outputs disabled		-	15	-	-	-	pF
		3 V port: nBn to nAn; $V_{CC(B)} = 5 \text{ V}; V_{CC(A)} = 3.3 \text{ V}$	[3][4]						
		outputs enabled		-	40	-	-	-	pF
		outputs disabled		-	5	-	-	-	pF

- [1] All typical values are measured at nominal voltage for  $V_{CC(B)}$  and  $V_{CC(A)}$  and at  $T_{amb} = 25 \, ^{\circ}C$ .
- [2]  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ .
  - ten is the same as tPZL and tPZH.
  - $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ .
- [3]  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).
  - $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$  where:
  - f<sub>i</sub> = input frequency in MHz;
  - f<sub>o</sub> = output frequency in MHz;
  - C<sub>L</sub> = output load capacitance in pF;
  - $V_{CC}$  = supply voltage in V;
  - N = number of inputs switching;
  - $\Sigma(C_L \times V_{CC}^2 \times f_0)$  = sum of outputs.
- [4] The condition is  $V_I = GND$  to  $V_{CC}$ .

### 11. AC waveforms



Measurement points are given in Table 8.

 $V_{OL}$  and  $V_{OH}$  are typical output voltage levels that occur with the output load.

Fig 5. Input (nAn, nBn) to output (nBn, nAn) propagation delays

74ALVC164245

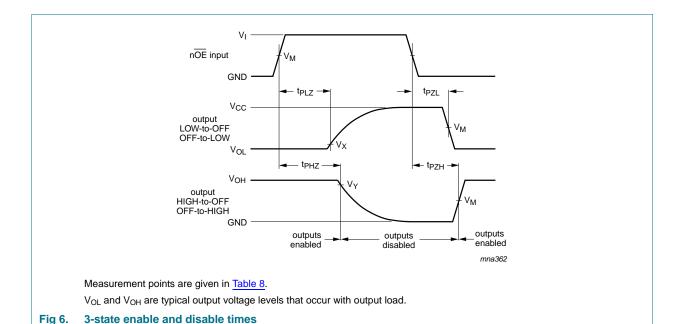
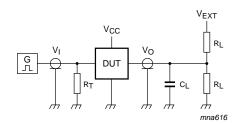


Table 8. Measurement points

Direction	Supply voltage		Input	Input		Output			
	V <sub>CC(A)</sub>	V <sub>CC(B)</sub>	VI	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>		
nAn port to nBn port	2.3 V to 2.7 V	2.7 V to 3.6 V	V <sub>CC(A)</sub>	$0.5 \times V_{CC(A)}$	1.5 V	V <sub>OL(B)</sub> + 0.3 V	$V_{OH(B)} - 0.3 V$		
nBn port to nAn port	2.3 V to 2.7 V	2.7 V to 3.6 V	2.7 V	1.5 V	$0.5 \times V_{CC(A)}$	V <sub>OL(A)</sub> + 0.15 V	V <sub>OH(A)</sub> – 0.15 V		
nAn port to nBn port	2.7 V to 3.6 V	4.5 V to 5.5 V	2.7 V	1.5 V	$0.5 \times V_{CC(B)}$	$0.2 \times V_{CC(B)}$	$0.8 \times V_{CC(B)}$		
nBn port to nAn port	2.7 V to 3.6 V	4.5 V to 5.5 V	3.0 V	1.5 V	1.5 V	$V_{OL(A)} + 0.3 V$	V <sub>OH(A)</sub> – 0.3 V		



Test data is given in <u>Table 9</u>.

Definitions for test circuit:

 $R_T$  = Termination resistance should be equal to output impedance  $Z_o$  of the pulse generator.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_L$  = Load resistance.

### Fig 7. Test circuit for measuring switching times

Table 9. Test data

Direction	Supply voltage		Load		V <sub>EXT</sub>		
	V <sub>CC(A)</sub>	V <sub>CC(B)</sub>	CL	R <sub>L</sub>	t <sub>PLH</sub> , t <sub>PHL</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
nAn port to nBn port	2.3 V to 2.7 V	2.7 V to 3.6 V	50 pF	500 Ω	open	GND	$2\times V_{CC}$
nBn port to nAn port	2.3 V to 2.7 V	2.7 V to 3.6 V	50 pF	500 Ω	open	GND	6.0 V
nAn port to nBn port	2.7 V to 3.6 V	4.5 V to 5.5 V	50 pF	500 Ω	open	GND	$2\times V_{CC}$
nBn port to nAn port	2.7 V to 3.6 V	4.5 V to 5.5 V	50 pF	500 Ω	open	GND	6.0 V

# 12. Package outline

SSOP48: plastic shrink small outline package; 48 leads; body width 7.5 mm

SOT370-1

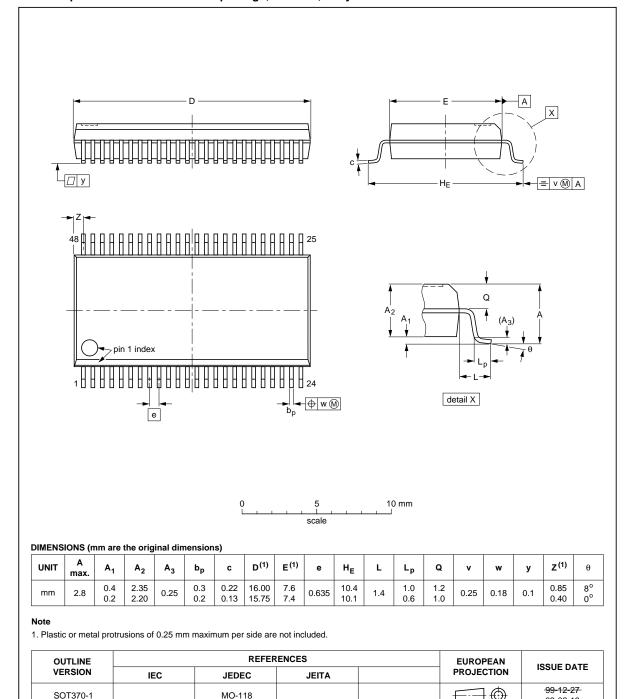


Fig 8. Package outline SOT370-1 (SSOP48)

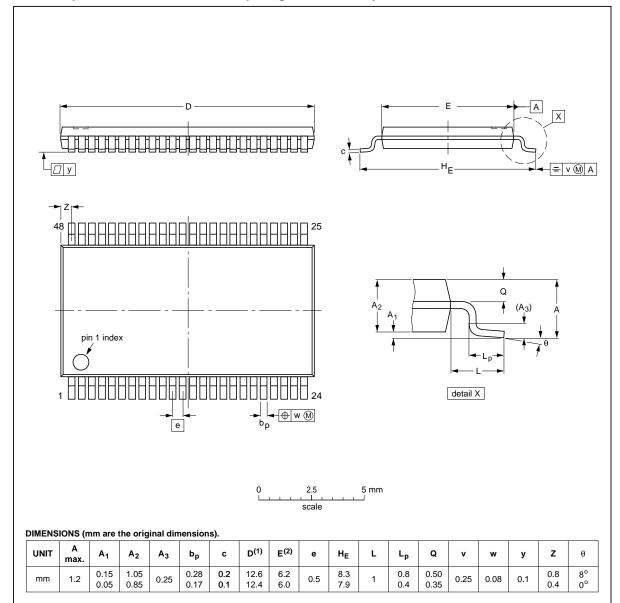
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03-02-19

### TSSOP48: plastic thin shrink small outline package; 48 leads; body width 6.1 mm

SOT362-1



#### Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE	REFERENCES				EUROPEAN	ICCUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT362-1		MO-153				<del>-99-12-27</del> 03-02-19

Fig 9. Package outline SOT362-1 (TSSOP48)

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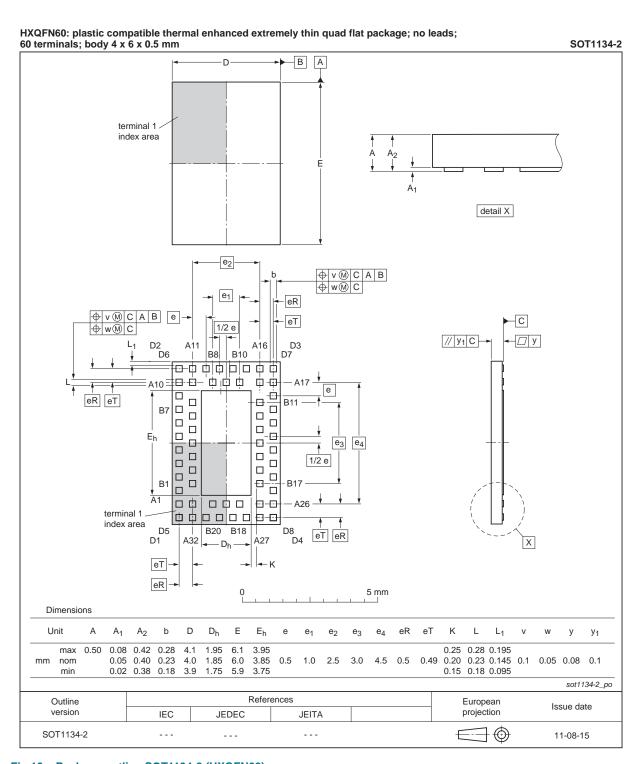


Fig 10. Package outline SOT1134-2 (HXQFN60)

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# 13. Abbreviations

### Table 10. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

# 14. Revision history

### Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVC164245 v.8	20120315	Product data sheet	-	74ALVC164245 v.7
Modifications:	<ul> <li>For type null</li> </ul>	mber 74ALVC164245BX the	e sot code has changed	to SOT1134-2.
74ALVC164245 v.7	20111117	Product data sheet	-	74ALVC164245 v.6
Modifications:	<ul> <li>Legal pages</li> </ul>	s updated.		
74ALVC164245 v.6	20110616	Product data sheet	-	74ALVC164245 v.5
74ALVC164245 v.5	20100413	Product data sheet	-	74ALVC164245 v.4
74ALVC164245 v.4	20081111	Product data sheet	-	74ALVC164245 v.3
74ALVC164245 v.3	20040914	Product data sheet	-	74ALVC164245 v.2
74ALVC164245 v.2	20040601	Product data sheet	-	74ALVC164245 v.1
74ALVC164245 v.1	19980826	Product specification	-	-

# 15. Legal information

#### 15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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